



Fermi
Gamma-ray Space Telescope

7th Fermi Symposium

Study of UGRB spatial anisotropy with P8 data

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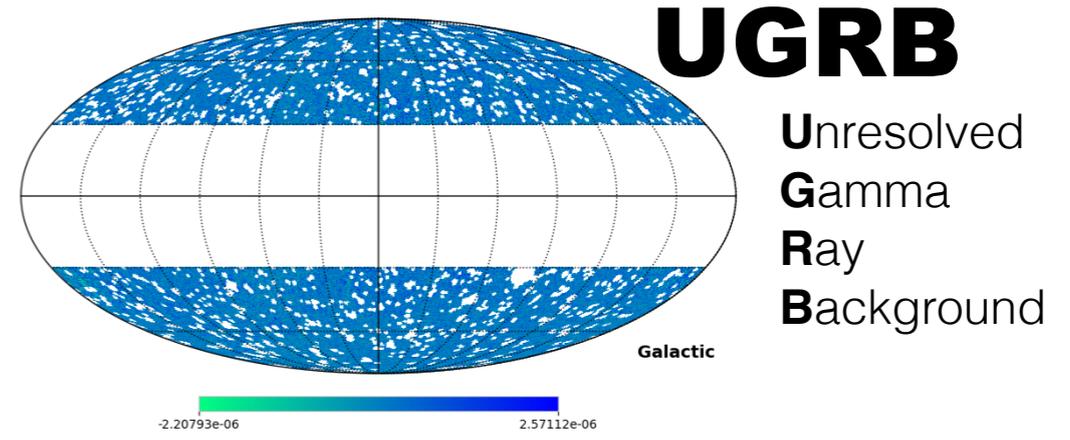
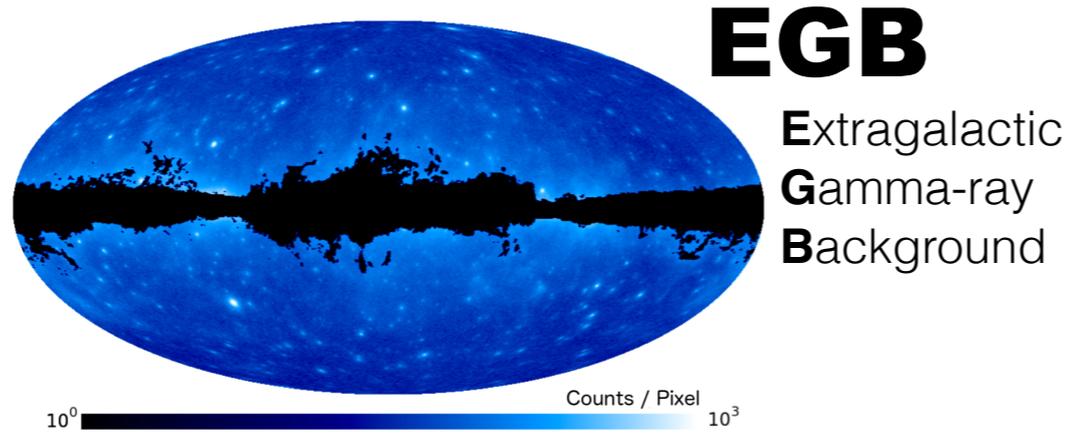
Michela Negro*
on behalf of *Fermi-LAT* collaboration

with

Nicolao Fornengo*
Marco Regis*

October 19th 2017

THE AIM

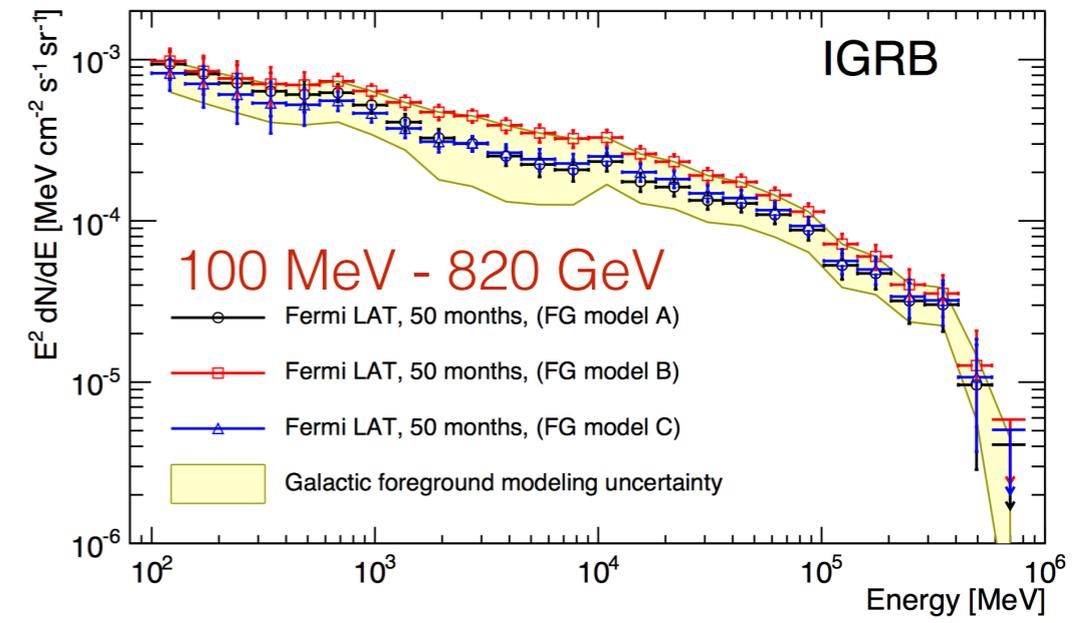


Explained by unresolved [2]

- ✱ Blazars
- ✱ Star-forming galaxies
- ✱ Radio galaxies

Different levels of anisotropies:
Angular Power Spectrum (APS)
can constrain UGRB nature! [3]

Intensity spectrum of the UGRB [1]



Other ways:

- ✱ 1-point photon count probability distribution of the UGRB
- ✱ X-correlation:
 - UGRB - galaxies (**See poster by Simone Ammazzalorso**)
 - UGRB - galaxy clusters
 - UGRB - weak lensing of cosmic shear
 - UGRB - gravitational lensing of the cosmic microwave background

[1] M. Ackermann et al. (Fermi-LAT), *Astrophys. J.* 799, 86 (2015), arXiv:1410.3696 [astro-ph.HE].
 [2] M. Ajello et al., *Astrophys. J.* 800, L27 (2015), arXiv:1501.05301 [astro-ph.HE]
 [3] S. Ando et al., (2017), arXiv:1701.06988v1 [astro-ph.HE]

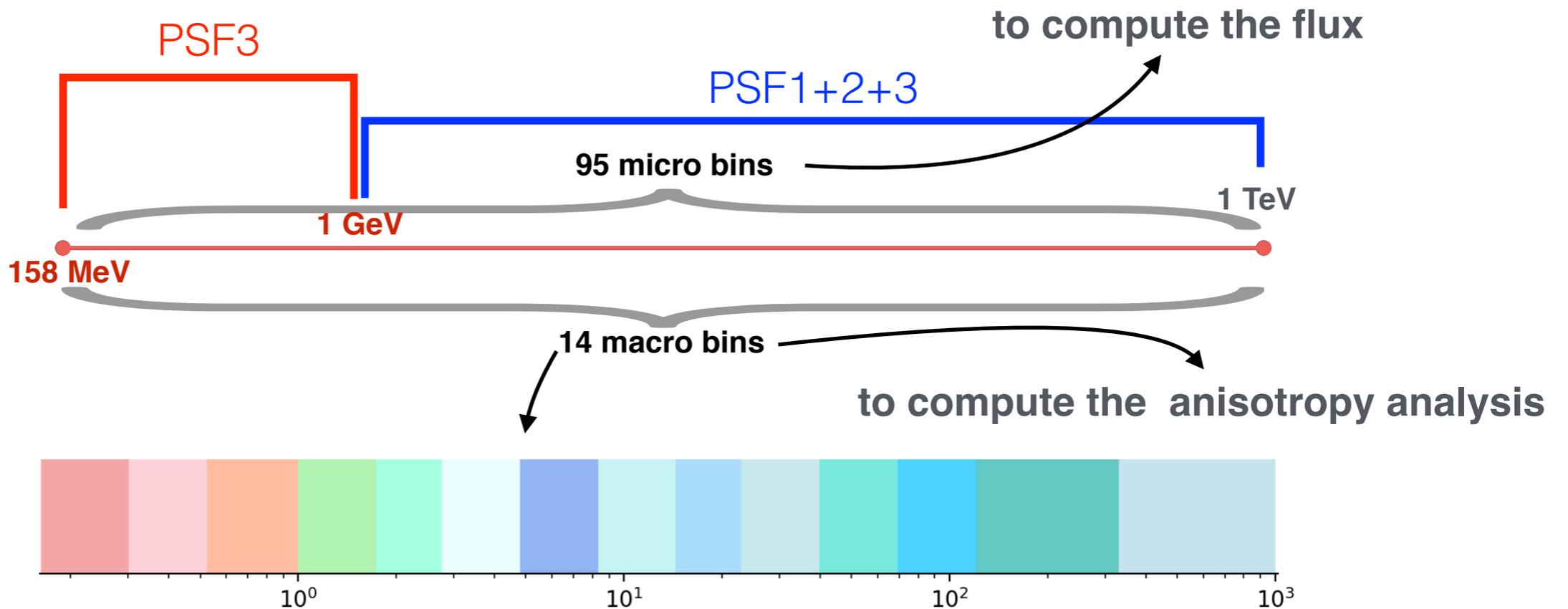
DATA SELECTION

Our selection:

- * 8 years, Pass 8
- * Event class: ULTRACLEANVETO (UCV)
- * Event type:
 - * PSF3 below 1 GeV
 - * PSF1+PSF2+PSF3 above 1 GeV

Previous work [1]:

- * 5 years, Pass 7 REP
- * Event class: ULTRACLEAN
- * Event type:
 - * FRONT
- * Energy range: 0.5 - 500 GeV



MASK (Φ , E)

- $|b| < 30$ deg
- 3FGL^[1] point-like and extended sources

POINT SOURCE MASK

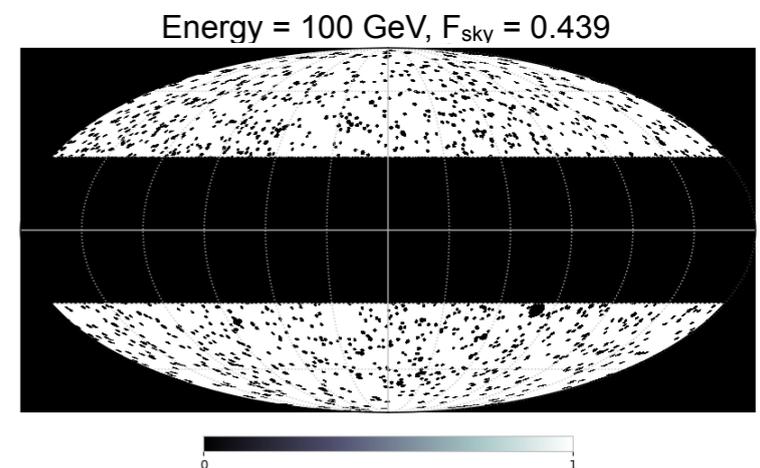
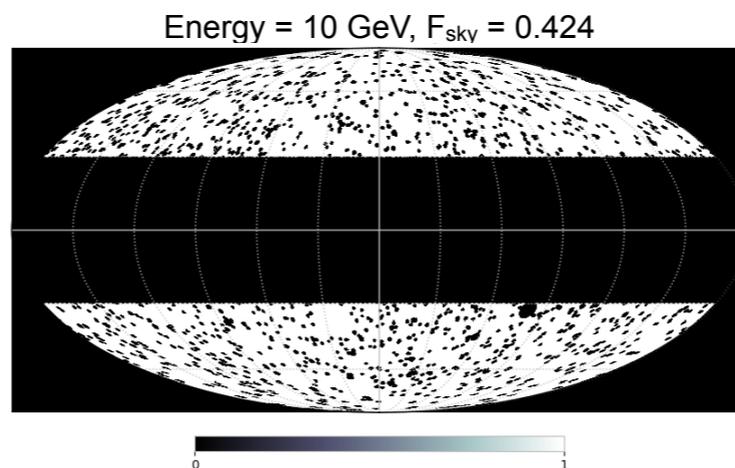
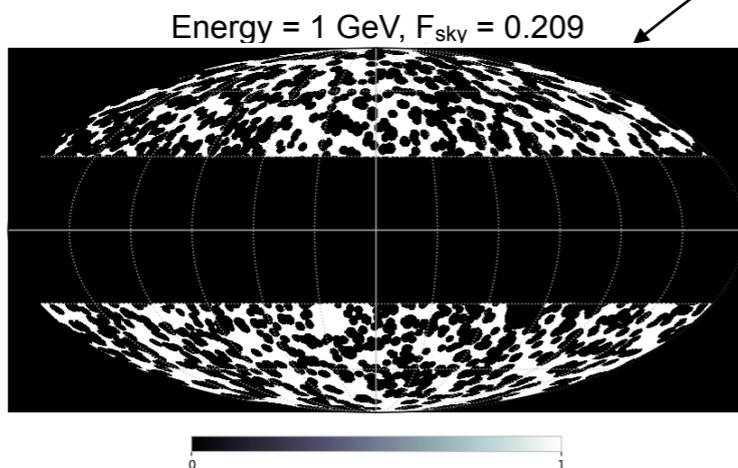
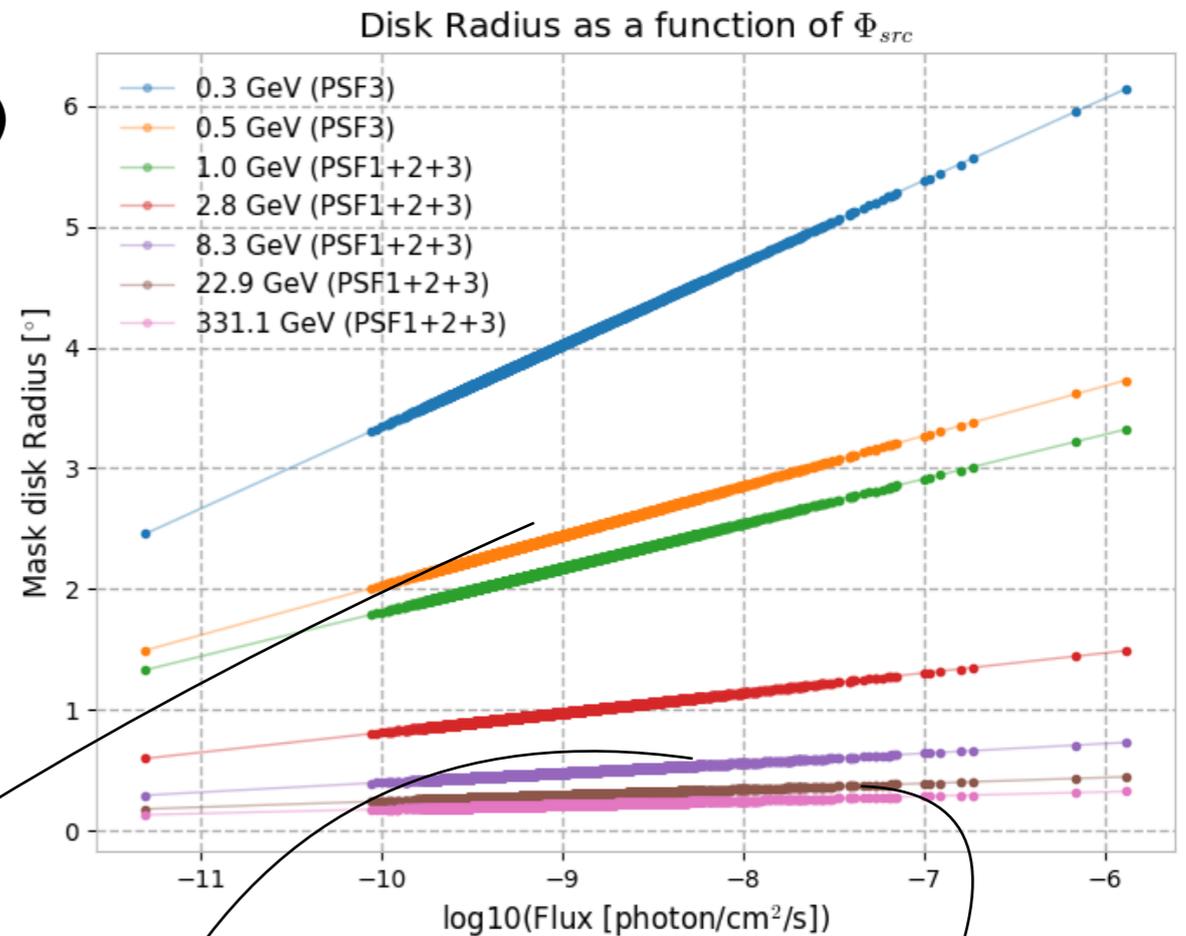
Circular region with **flux (Φ)** and **energy (E)** dependent radius:

- ✱ 2 x PSF(E) @ Φ_{\min}
- ✱ 5 x PSF(E) @ Φ_{\max}
- ✱ Varying logarithmically with Φ

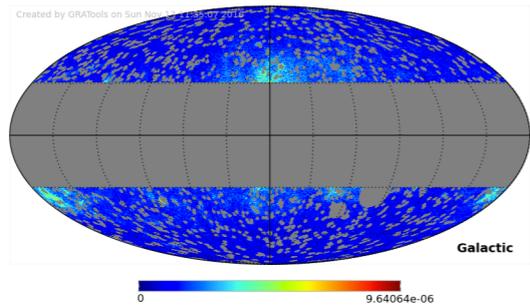
EXTENDED SOURCE MASK

Circular region with radius:

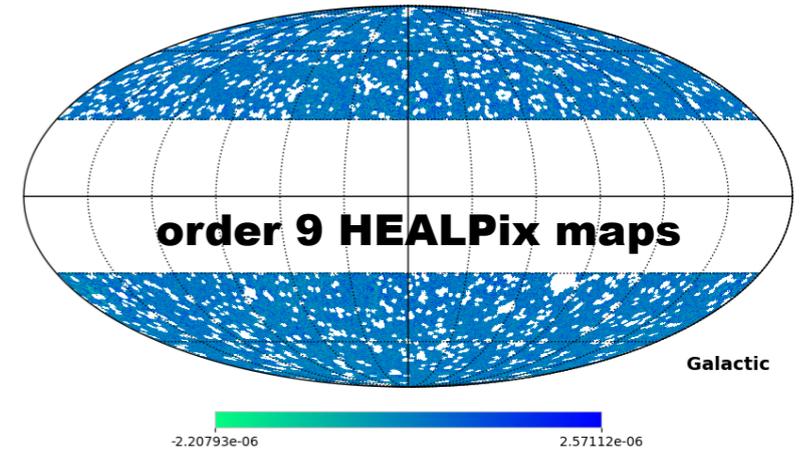
- ✱ 10x PSF(E) for CenA and LMC
- ✱ 5 x PSF(E) for all the others



ANGULAR POWER SPECTRUM



FOREGROUND SUBTRACTION [1]



From Intensity...

$$I(E, \theta)^{meas} = I(E, \theta)^{sig} \times PSF(E, \theta) + I_N(E)$$

decomposition into spherical harmonics:

$$C_l \approx \langle \left\| \int d\vec{n} \delta I Y(\vec{n})^* \right\|^2 \rangle$$

Using PolSpice [2]

$$C_{l,E}(l)^{PolSpice} = C_{l,E}(l)^{sig} \times W_E(l)^2 + C_{N,E}$$

... to Angular Power Spectrum

WHITE NOISE CORRECTION

$$C_N = \frac{n_{\gamma, pix}^i / (A_{pix}^i)^2}{\Omega_{pix}} \quad [3]$$

$$C_{l,E}(l)^{sig} = \frac{C_{l,E}(l)^{PolSpice} - C_{N,E}}{W_E(l)^2}$$

PSF and RESOLUTION CORRECTION [3]

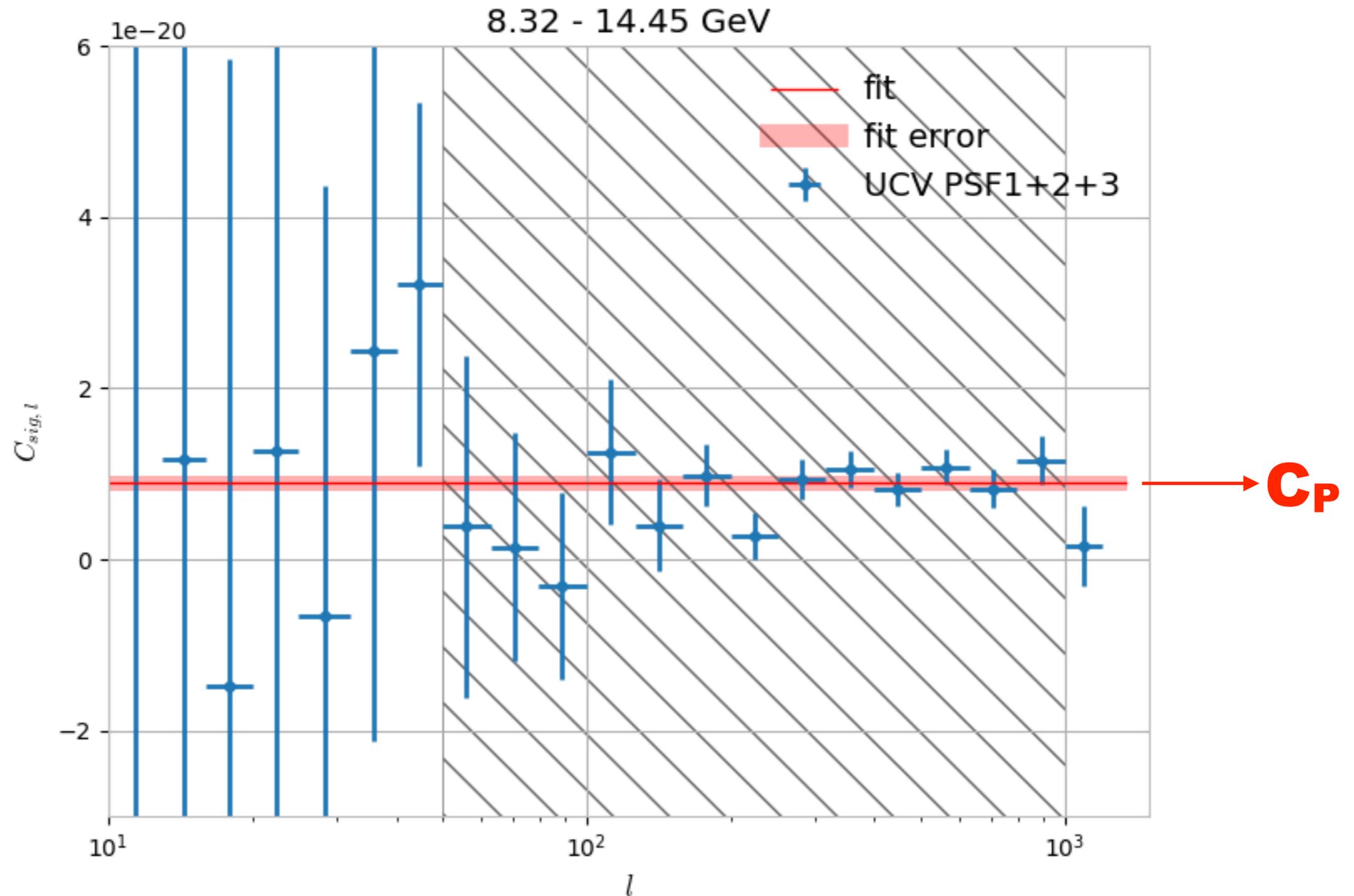
$$W_E(l) = \frac{\int_{E_{min}}^{E_{max}} W(E, l) \frac{dN}{dE} dE}{\int_{E_{min}}^{E_{max}} \frac{dN}{dE} dE}$$

$$W(E, l) = W^{beam}(E, l) \cdot W^{pix}(l)$$

$$W_l^{beam}(E) = 2\pi \int_{\theta_{min}}^{\theta_{max}} P_l(\cos\theta) PSF(\theta; E) \sin\theta d\theta$$

FROM APS TO $C_P(E)$ - 1

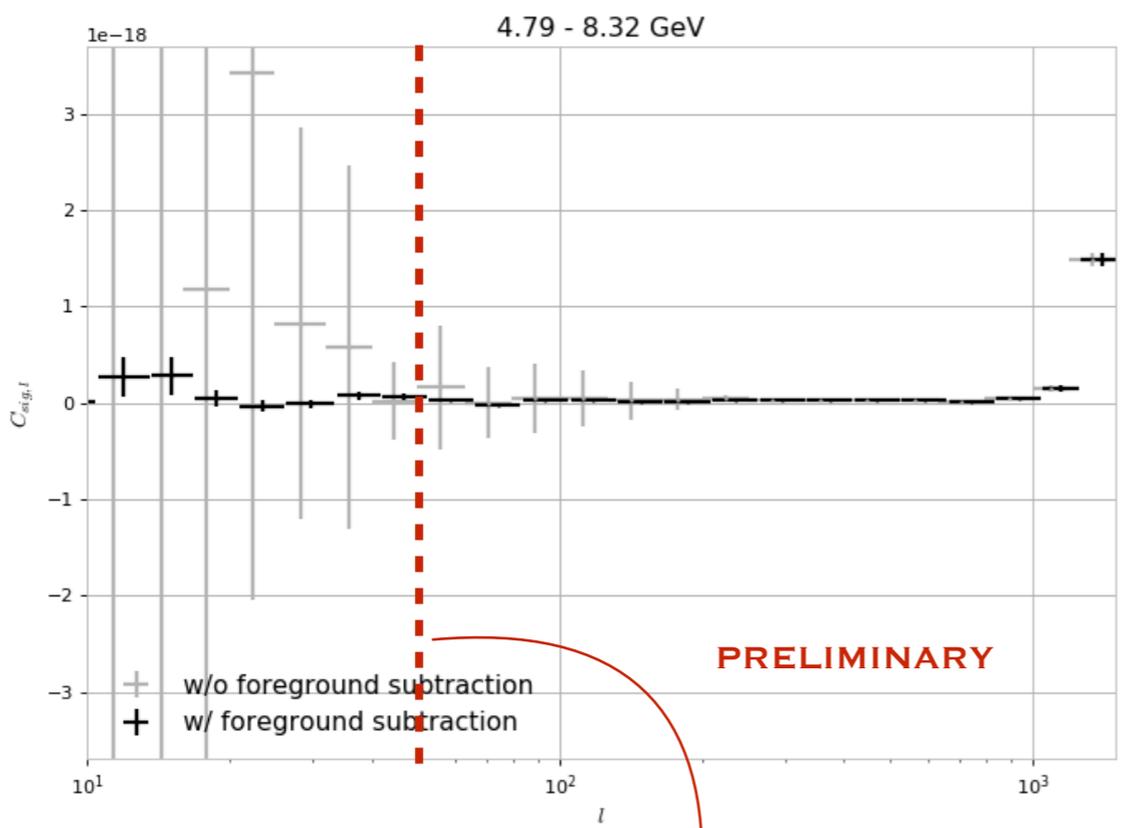
Hp: anisotropy dominated by shot noise of point-like sources \rightarrow random distribution \rightarrow flat APS



FROM APS TO $C_P(E)$ - 2

For each energy bin we define the range of multipoles to fit

@ LOW-MULTIPOLES
Residual foreground contamination



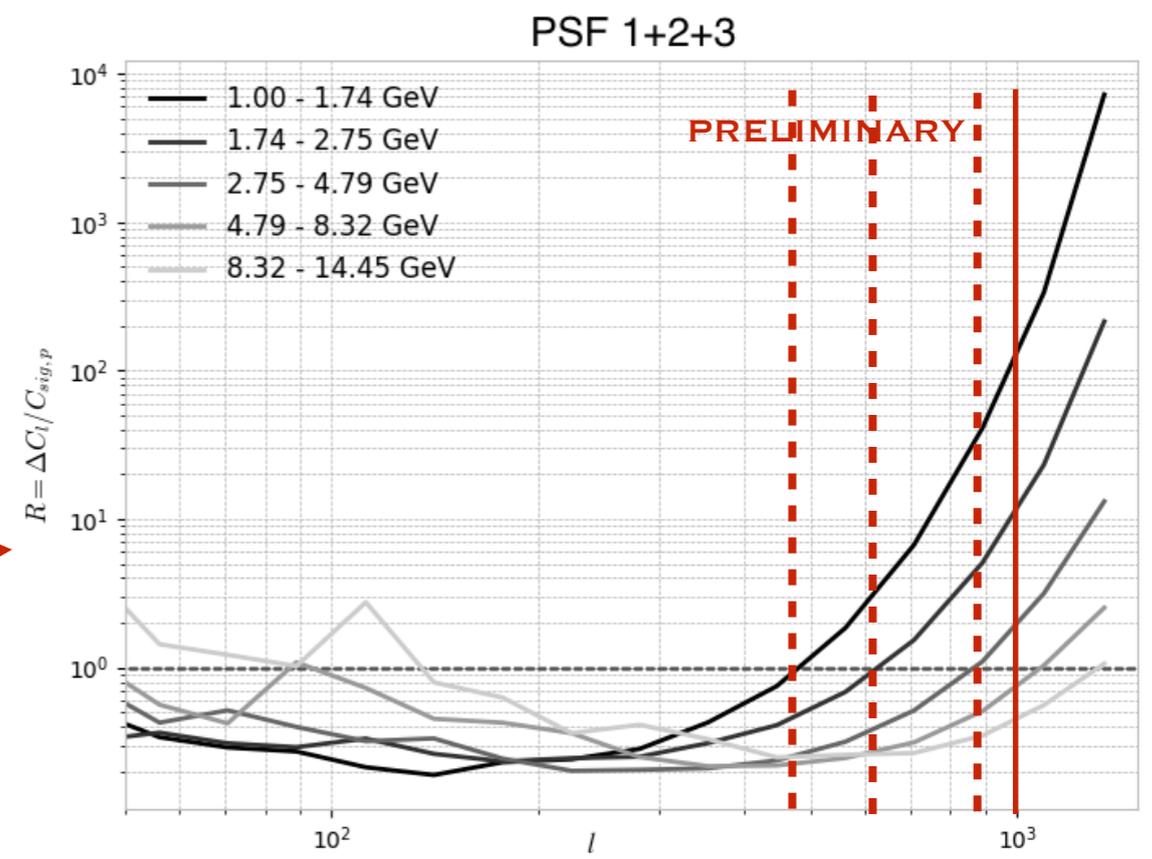
$l_{min} = 50$ [1]

$l_{max}(E)$

@ HIGH-MULTIPOLES
PSF correction can be inaccurate

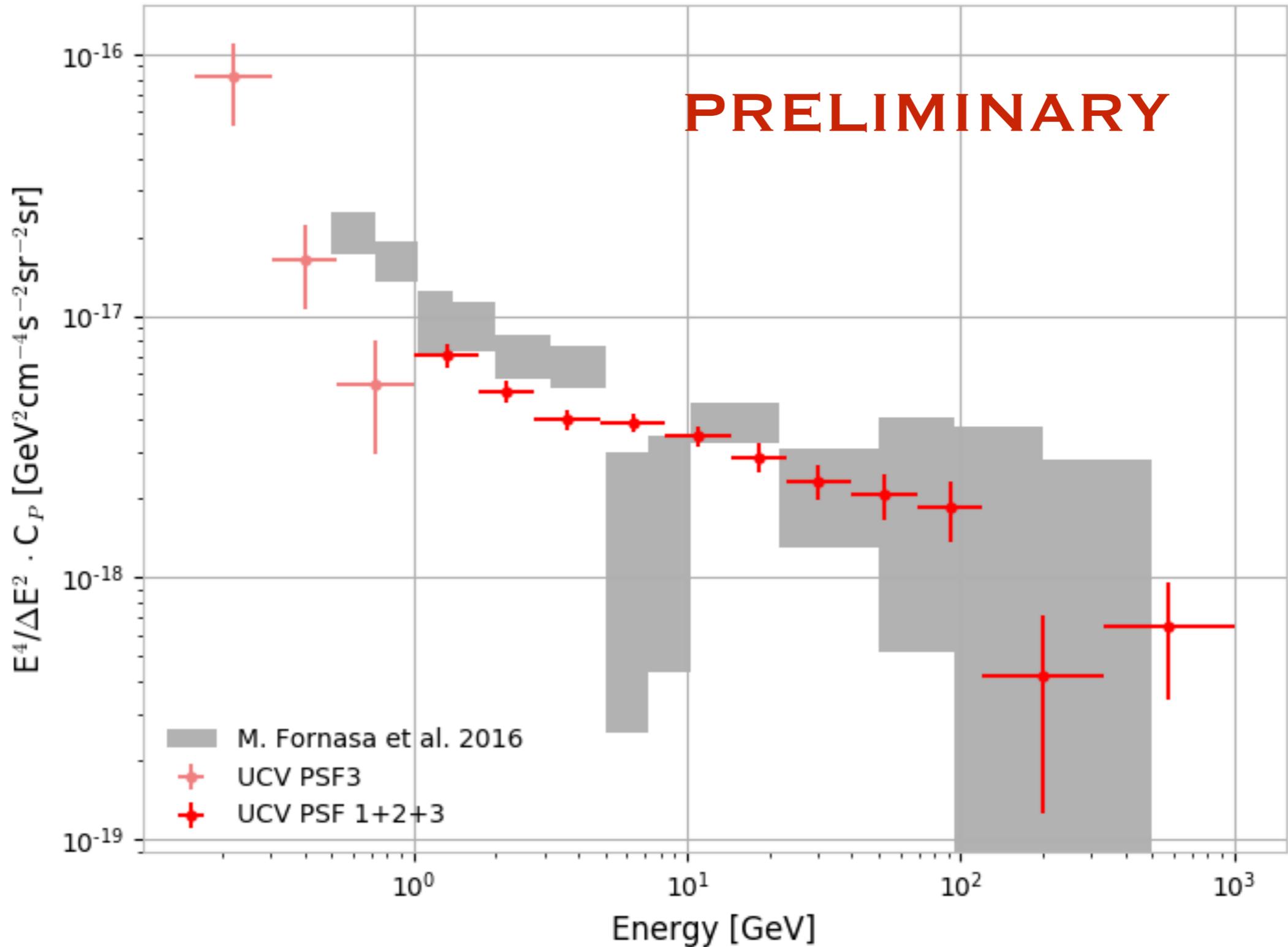
$$R(l_{max}) = \frac{\Delta C_l(l_{max})}{C_P^{l_{max}}} > 1$$

$$\Delta C_l = \sqrt{\frac{2}{(2l+1)f_{sky}} \left(C_l + \frac{C_N}{W_l^2} \right)}$$





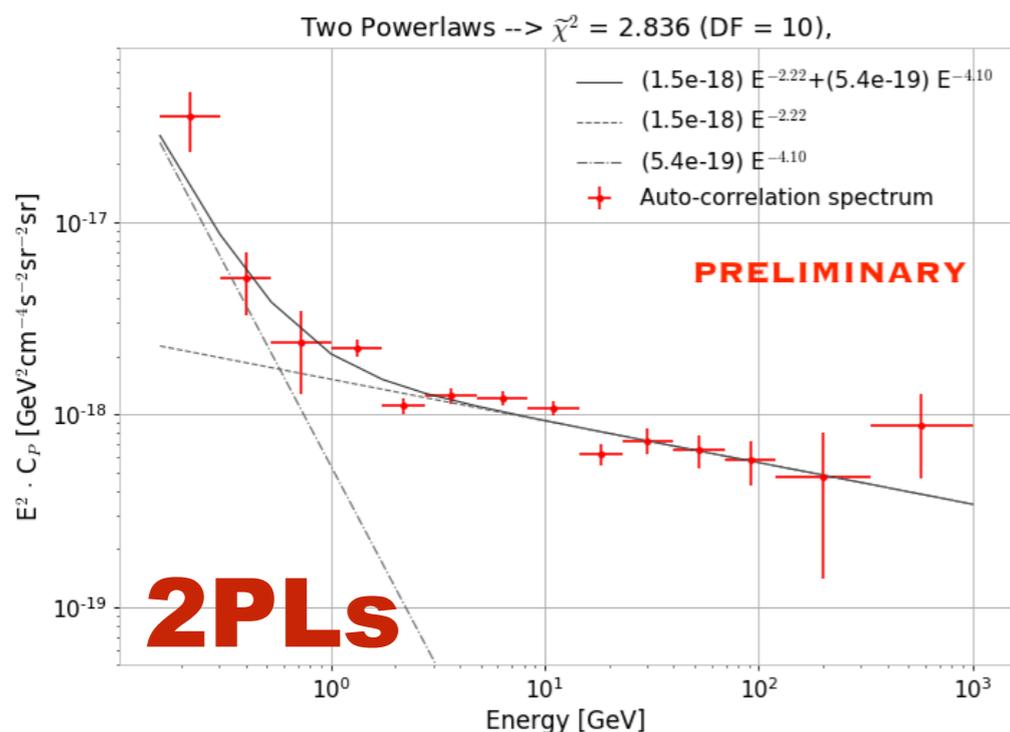
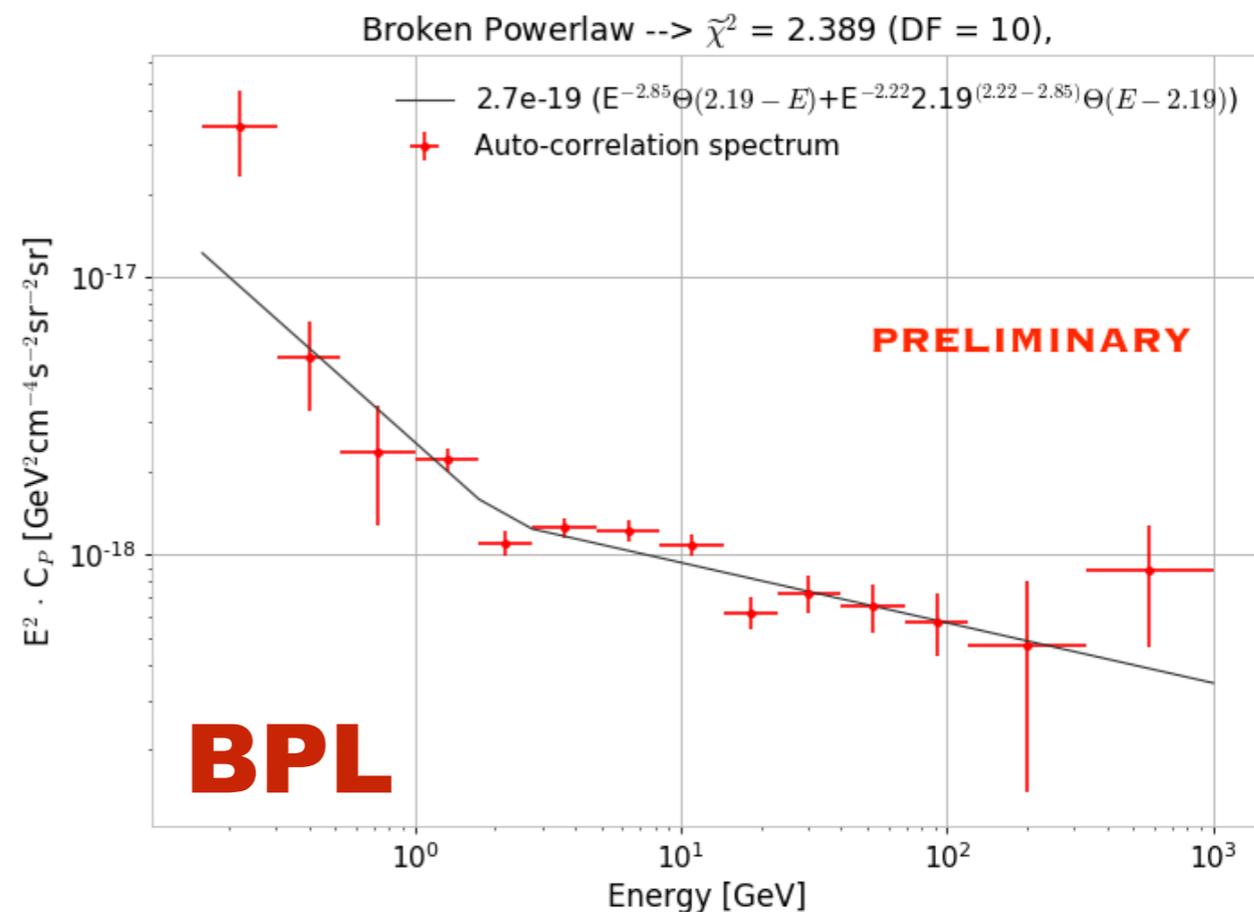
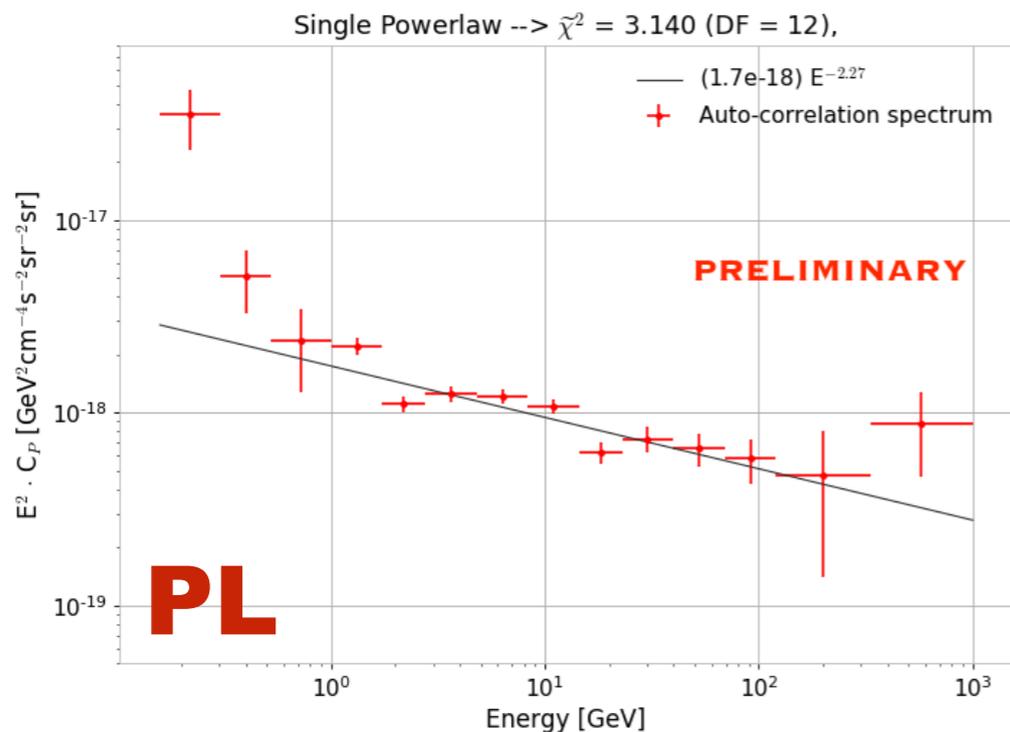
ANISOTROPY ENERGY SPECTRUM



FIT OF AUTO-CORRELATION ENERGY SPECTRUM

Three hypothesis tested:

1. **PL** → single power law
2. **2PLs** → 2 power laws
3. **BPL** → broken power law



“Break” scenario is favoured, which can mean:

1. one class of unresolved srcs with a break in the spectrum
2. two classes with PL spectra
3. ???



CROSS-CORRELATIONS IN ENERGY BINS

CROSS-CORRELATION in ENERGY BINS

CROSS-CORRELATION COEFFICIENT [1]

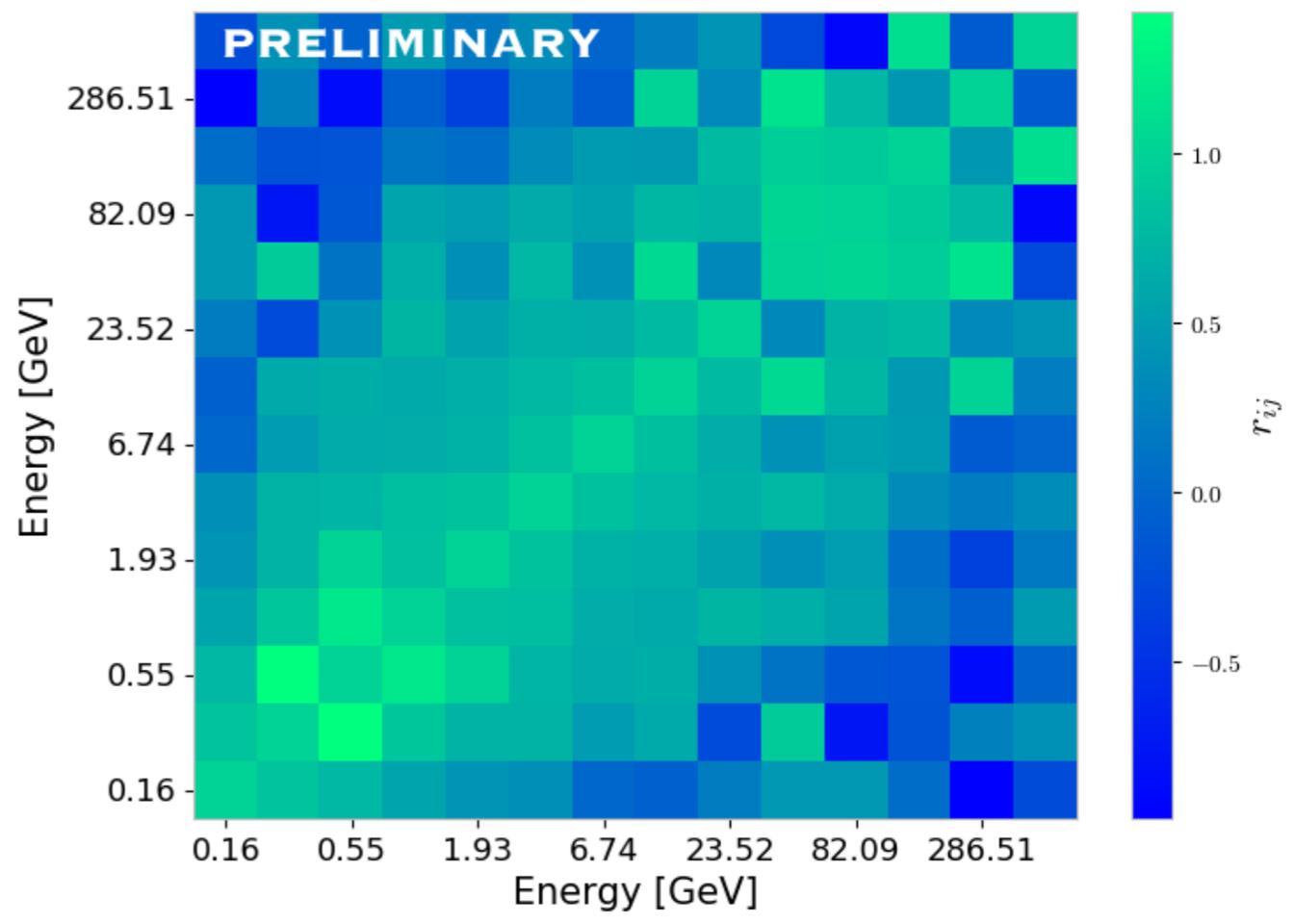
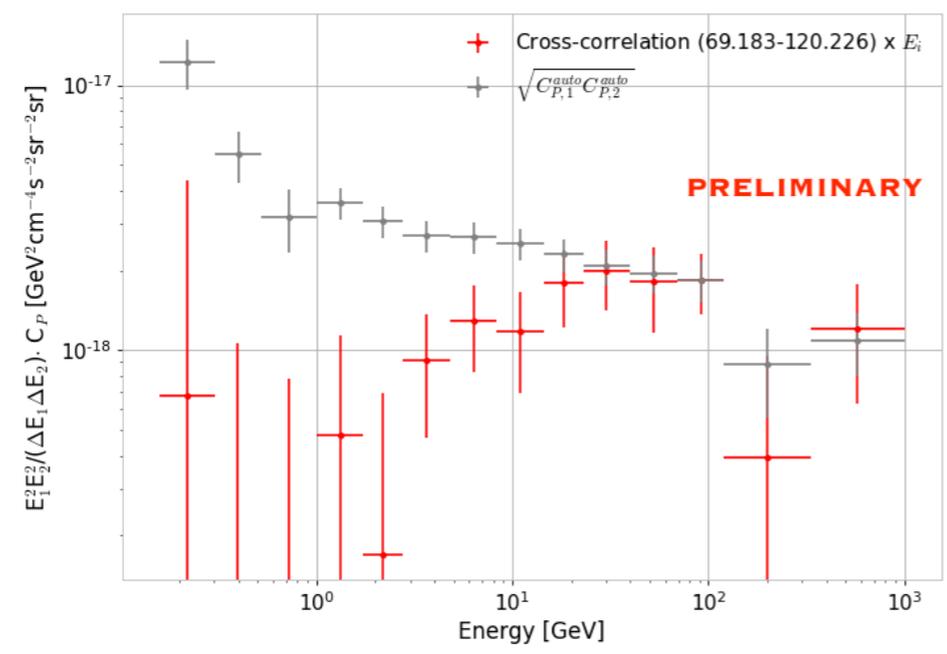
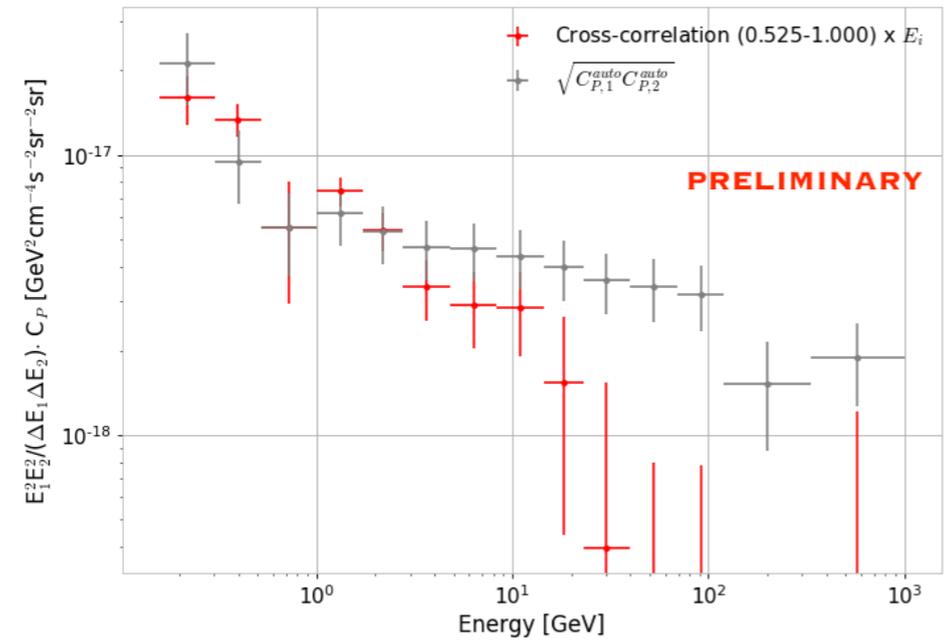
$$r_{ij} = \frac{C_P^{ij}}{\sqrt{C_P^{ii} C_P^{jj}}}$$

1. one class $r_{ij} = 1$

2. two classes $r_{ij} < 1$

$$C_p^{i,j} = \int \frac{dN}{dS} S^i S^j dS$$

$$S(E) \propto E^{-\beta}$$

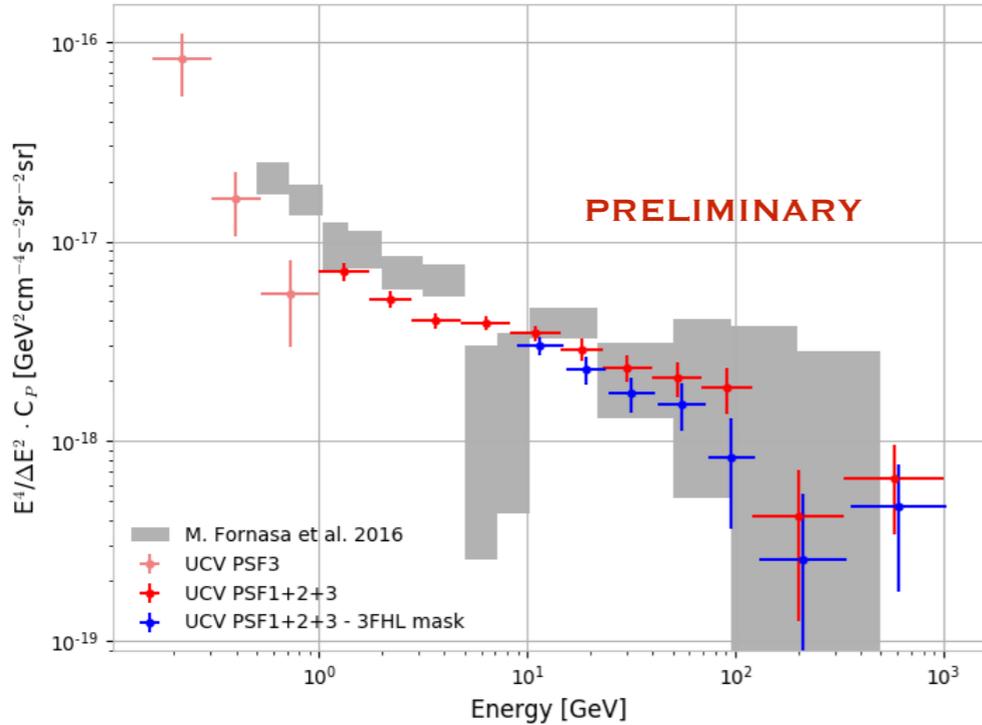


... unless due to threshold dependent effects...

SOURCE CATALOG DEPENDENCE

ANISOTROPY ENERGY SPECTRUM CHANGES BY CHANGING THE MASKED SOURCE CATALOG

3FGL VS 3FHL^[1] @ E > 10 GeV



The physical interpretation is not trivial!

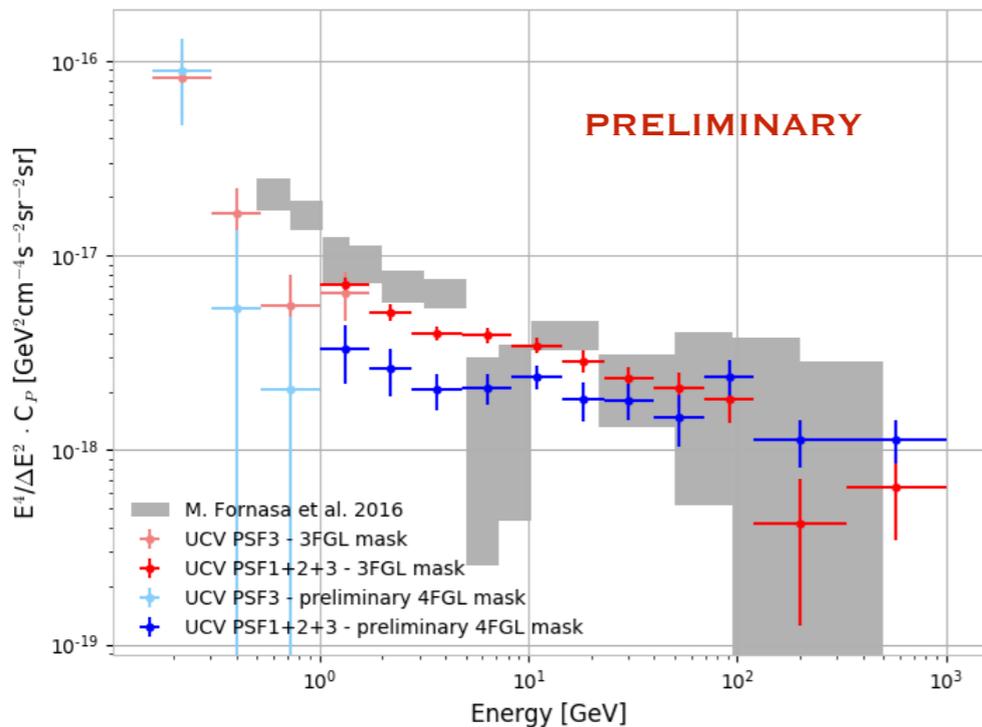
$$C_p = \int_0^{S_{max}} (1 - \omega(S')) S'^2 \frac{dN}{dS'} dS'$$

Need to know the **detection efficiency** of the instrument for the catalog used, possibly in **each energy bin**.

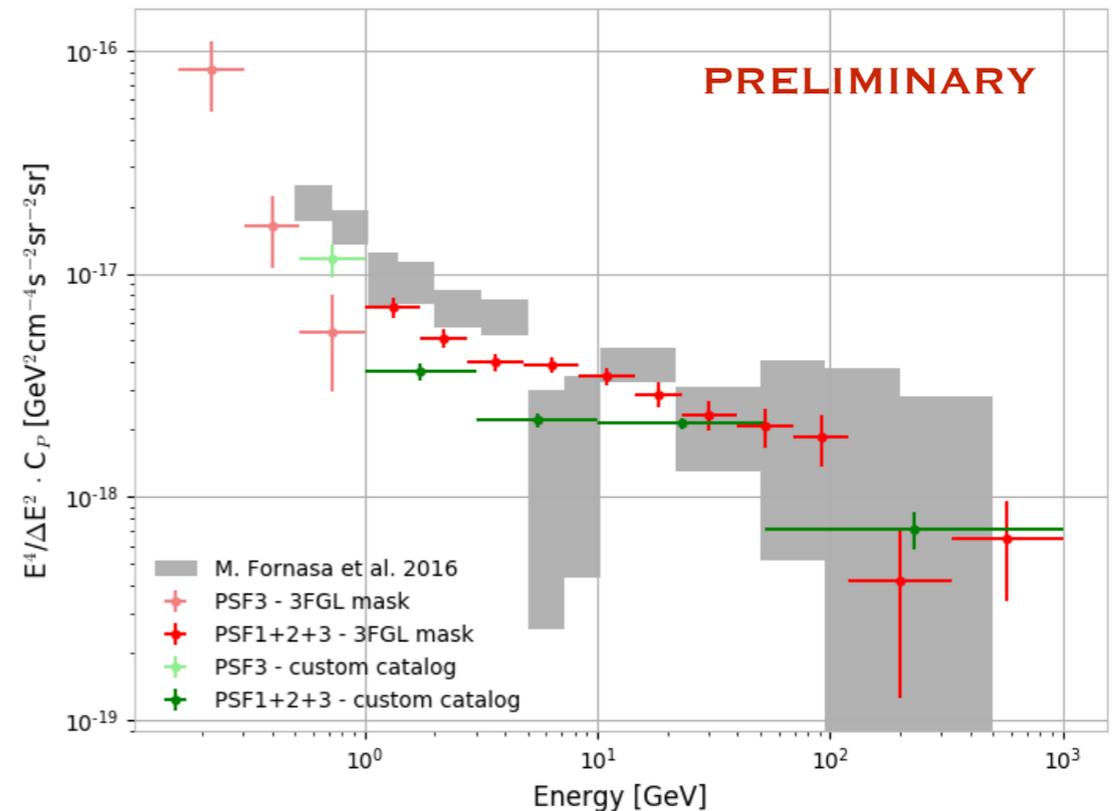
Future plans:

produce "custom catalogs" in different energy bins (Fermi Tools) and estimate the detection efficiency via simulations

3FGL VS ~4FGL^[2]



3FGL VS Custom Src List^[3] in 5 E bins





Fermi Gamma-ray Space Telescope

SUMMARY & CONCLUSIONS

- * Analysis aspects:
 - * General improvement of data with Pass 8:
 - * more statistics,
 - * cleaner data selection and
 - * PSF types
 - * Energy-dependent analysis: Masks, multipole range
- * APS and X-corr suggest multiple populations of unresolved sources, but interpretation needs more studies
- * Assess APS dependance on point source catalog that is masked and its detection efficiency

SPECIAL ACKNOWLEDGMENTS

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Prof.s **Nicolao Fornengo** and **Marco Regis**

Fermi-LAT Collaboration

THANK YOU FOR YOUR ATTENTION!

backup

WINDOW FUNCTIONS

$$W_l = W_l^{beam} \cdot W_l^{pix}$$

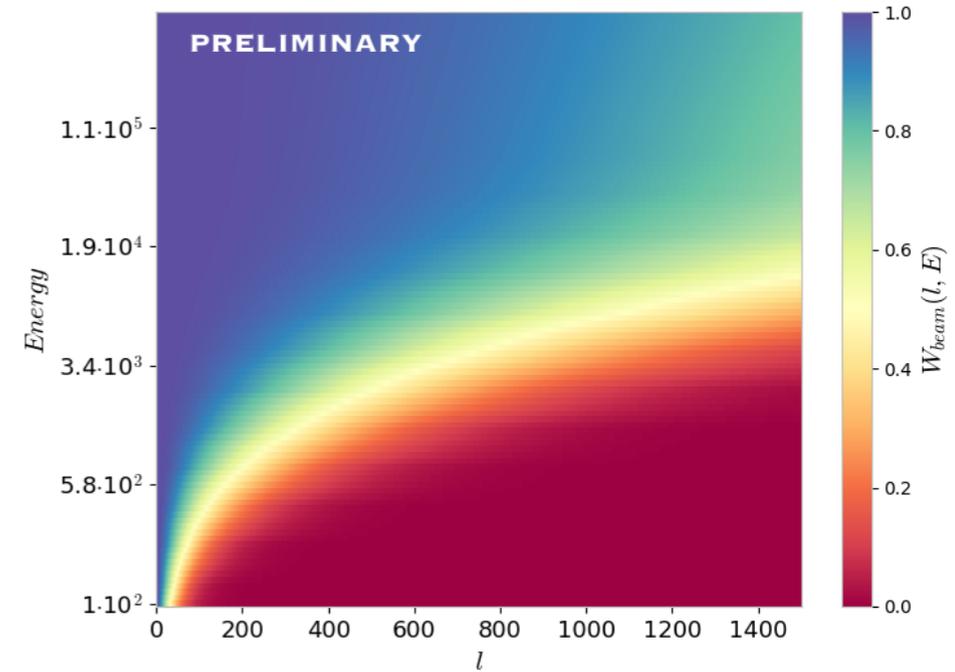
PIXEL WINDOW FUNCTION: RESOLUTION CORRECTION ~ 1 for order 9 maps

BEAM WINDOW FUNCTION: PSF CORRECTION

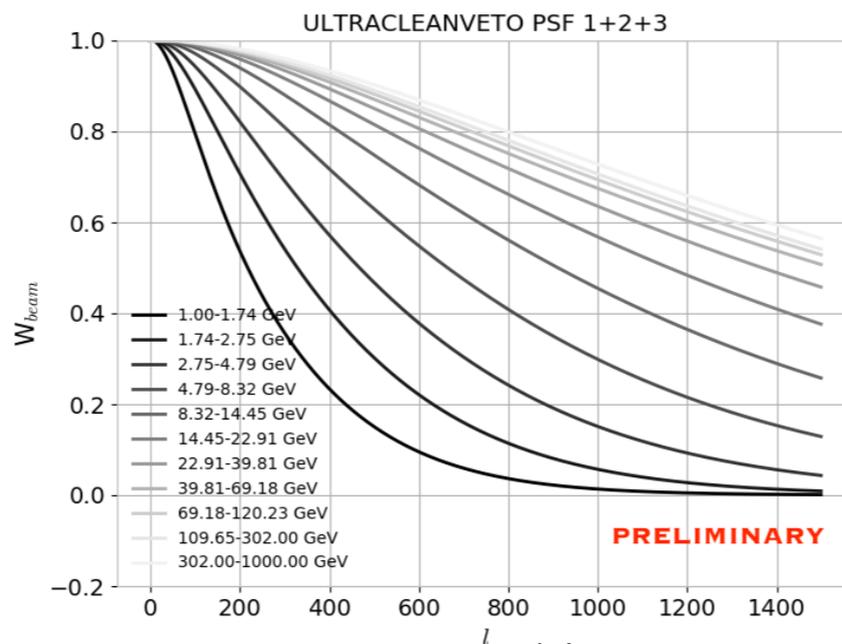
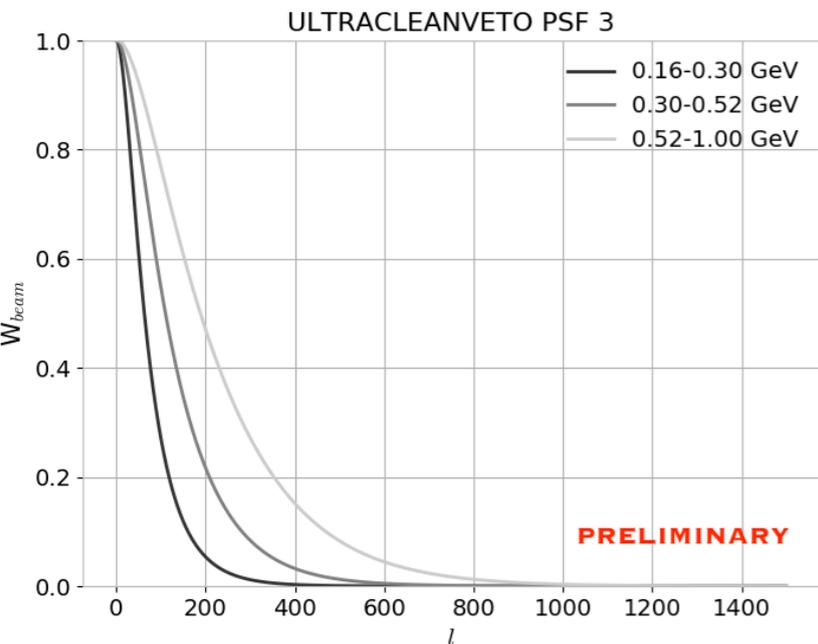
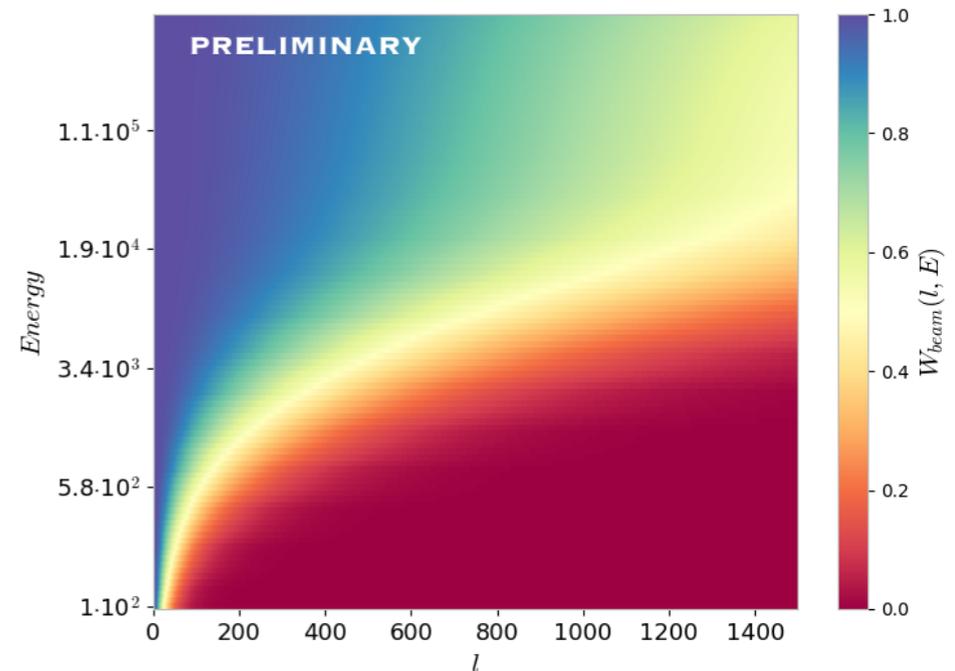
$$W_l^{beam}(E) = 2\pi \int_{\theta_{min}}^{\theta_{max}} P_l(\cos\theta) PSF(\theta; E) \sin\theta d\theta$$

$$\langle W_l \rangle = \frac{\int_{E_{min}}^{E_{max}} W_l(E) \frac{dN}{dE} dE}{\int_{E_{min}}^{E_{max}} \frac{dN}{dE} dE} \quad dN/dE \sim E^{-2.3}$$

PSF 3



PSF 1+2+3



FOREGROUND SUBTRACTION

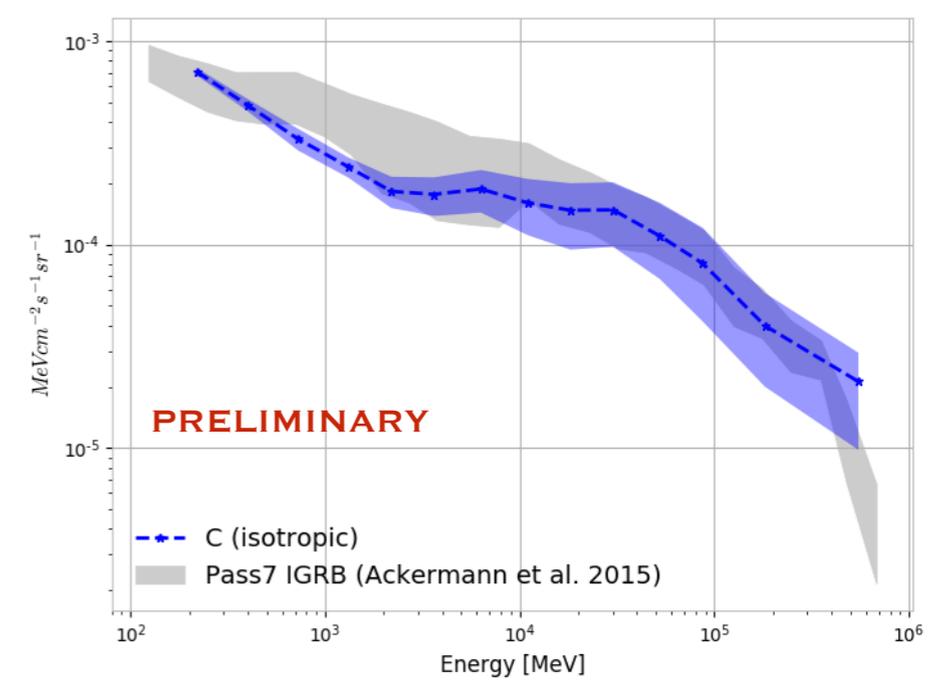
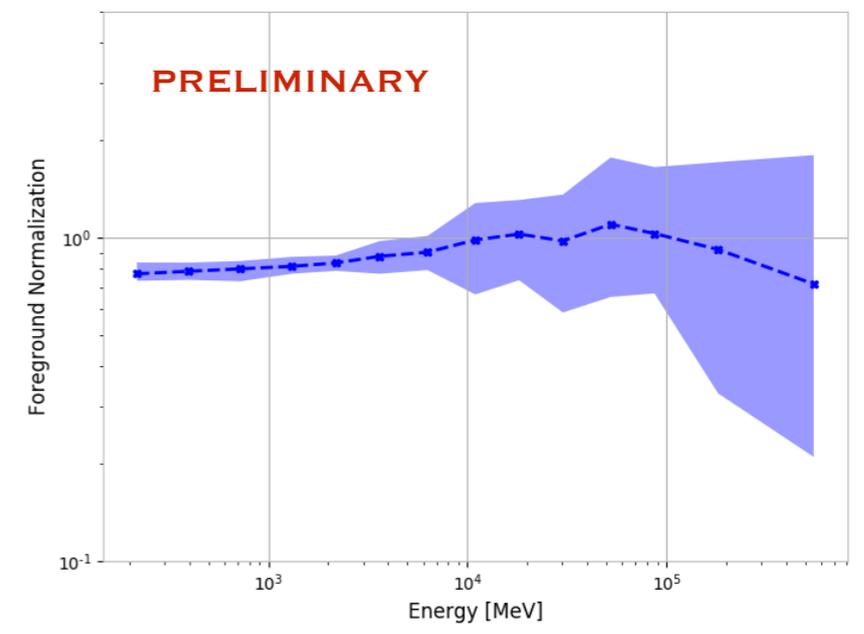
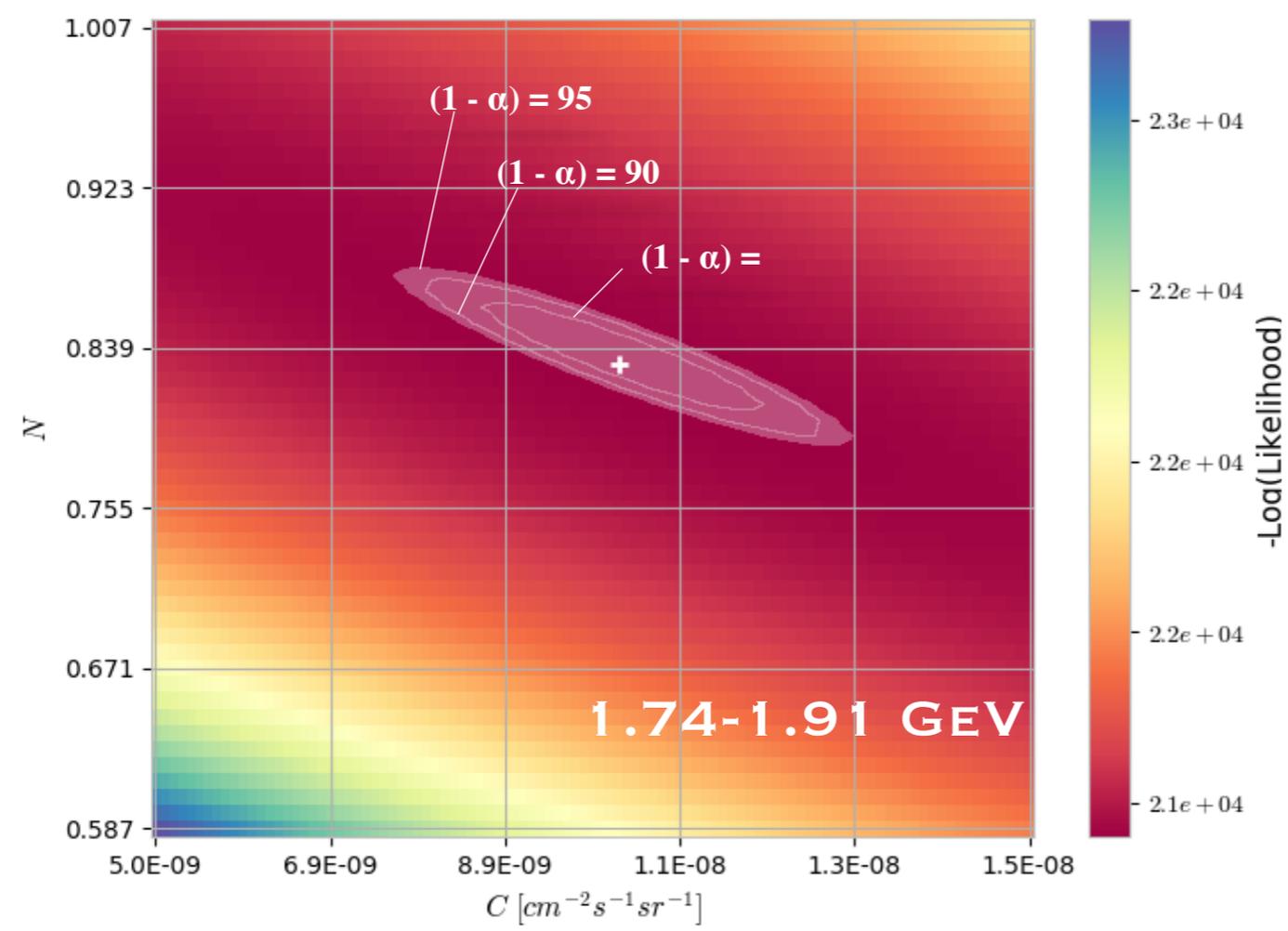
Galactic diffuse emission model: **gll_iem_v6.fits**

$$\Phi_{data} = N\Phi_{model} + C$$

$$\log(L) = \sum_{i^{th} \text{ pixel}} D_i \log(F_i) - F_i - \log(D_i!)^{[1]}$$

$$F_i = N\Phi_{fore} + C$$

pixels outside the mask



Pass 8 PSF 68% cont. [1]

